

Notice of References Cited	Application/Control No. 10/840,110		Applicant(s)/Patent Under Reexamination WEEL, MARTIN	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0267899 A1	12-2004	Rahman et al.	709/217
*	B	US-2005/0060264 A1	03-2005	Schrock et al.	705/051
*	C	US-2004/0249708 A1	12-2004	Jacobs et al.	705/014
*	D	US-6,526,411 B1	02-2003	Ward, Sean	707/102
*	E	US-6,990,497 B2	01-2006	O'Rourke et al.	707/101
*	F	US-2004/0086120 A1	05-2004	Akins et al.	380/240
*	G	US-2003/0182315 A1	09-2003	Plastina et al.	707/200
*	H	US-2003/0225834 A1	12-2003	Lee et al.	709/204
*	I	US-2003/0093790 A1	05-2003	Logan et al.	725/38
*	J	US-2003/0227478 A1	12-2003	Chatfield, Keith M.	345/751
*	K	US-2002/0166123 A1	11-2002	Schrader et al.	725/58
*	L	US-2002/0032019 A1	03-2002	Marks et al.	455/414
*	M	US-7,020,710 B2	03-2006	Weber et al.	709/232

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0060264	03-2005	Schrock et al.	705/051
*	B	US-2005/0113946	05-2005	Janik, Craig M.	700/094
*	C	US-2004/0255340	12-2004	Logan, James D.	725/145
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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